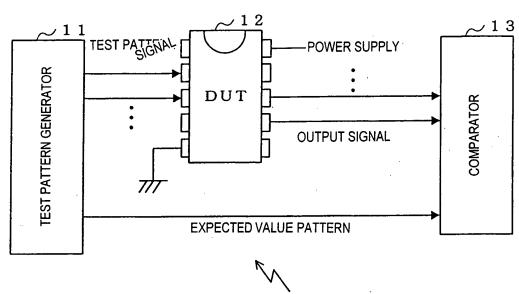
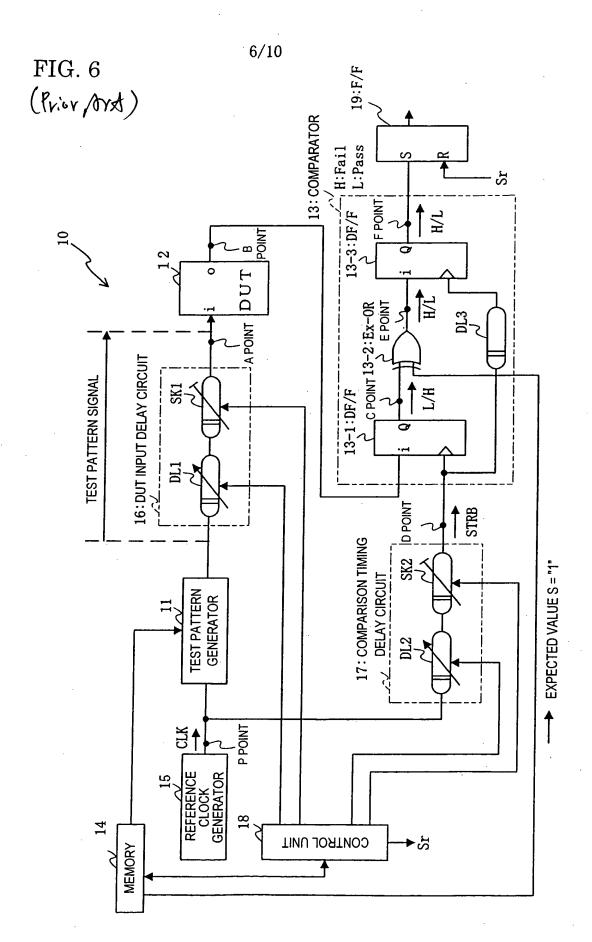
FIG. 5 (Prior/rxt)



1 0 : SEMICONDUCTOR TEST APPARATUS



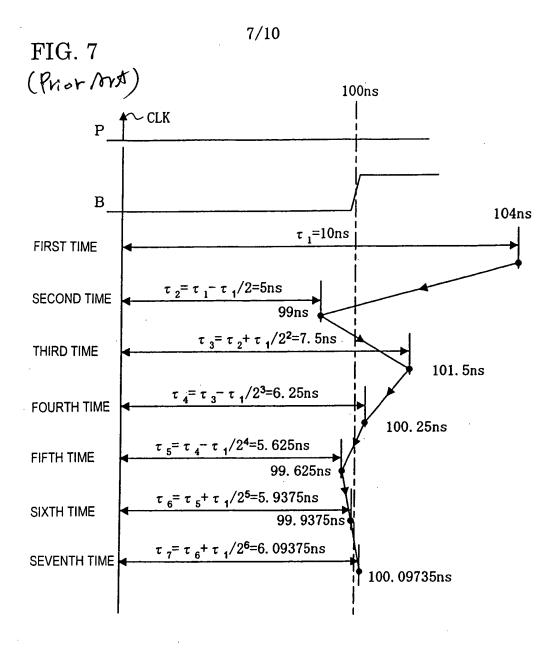


FIG. 8 (Prior Art)

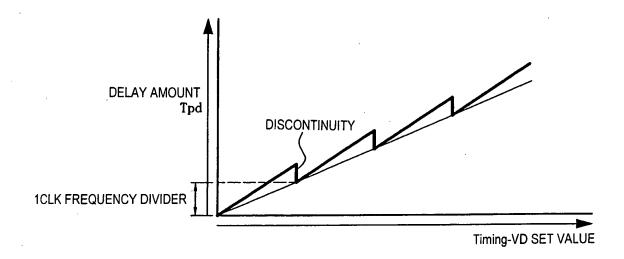
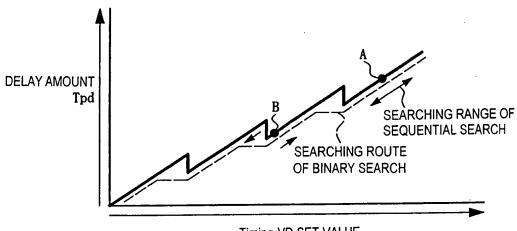


FIG. 9 (Prior And)



Timing-VD SET VALUE

FIG. 10 (Prior MA)

